


<b>Search Notes</b>  	<b>Application/Control No.</b>  10581114	<b>Applicant(s)/Patent Under Reexamination</b>  HEIDECHE ET AL.
	<b>Examiner</b>  Son T Nguyen	<b>Art Unit</b>  3643

SEARCHED			
Class	Subclass	Date	Examiner
47	57.5	1/15/2011	stn

SEARCH NOTES		
Search Notes	Date	Examiner
IPC foreign search, and text search, see printouts	1/15/2011	stn

INTERFERENCE SEARCH			
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	/Son T Nguyen/ Primary Examiner.Art Unit 3643
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